

13th International Conference on Quality Control by Artificial Vision

QCAV 2017

May 14 - 16, 2017,
Surugadai Memorial Hall, Chuo University,
Tokyo, JAPAN

<http://www.tc-iaip.org/QCAV2017/>

2nd CALL FOR PAPERS

Scope of Conference

The objective of the QCAV2017 conference is to provide a forum for researchers, engineers, suppliers and users of vision systems to present and discuss the state-of-the-art in machine and computer vision and image processing techniques, with an emphasis on quality control.

The conference will also offer an opportunity to fill the gap between artificial vision and image processing community and people working in application fields.

Conference Topics

Papers describing novel theoretical, experimental, and applied work in image processing and computer vision for quality control are welcomed.

Papers are solicited from, but not limited to, the following categories:

- Optical, Electron, X-ray, Ultrasound and other Imaging Modalities
- Image Acquisition, Vision Sensors and Systems
- Non-destructive Testing and Metrology
- Image Processing and Segmentation
- Image Interpretation and Pattern Recognition
- Image Analysis and Geometrical Description
- Process Automation, Characterization and Control

The Proceedings are published in the **SPIE Digital Library**.

Plenary Speakers

Stéphane Canu (INSA de Rouen, Normandie Université, France)

Mohit Gupta (University of Wisconsin-Madison, USA)

Yukiyasu Domae (Mitsubishi Electric Corporation, Japan)

Conference Venue

The conference will be held at the "Surugadai Memorial Hall", Chuo University that is located near Ochanomizu Station. Ochanomizu section is a neighbor of various recommended tourist attractions such as Akihabara or Ueno.



Submission Guidelines

QCAV17 authors will submit their manuscripts via the SPIE portal:

<http://spie.org/paper-submission-qcav17>

The authors can access the above URL from QCAV17 conference website.

Important dates

Submission of abstract: ~~Oct. 14, 2016~~ Nov. 4, 2016

Notification of Acceptance: Dec. 15, 2016

Submission of camera-ready paper: Jan. 16, 2017

Publication date of proceedings: May 14, 2017

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